

**Hideo Fujiwara has been honored with  
the IEEE TTTC Lifetime Contribution Medal  
at ITC 2020 on November 3, 2020.**



INTERNATIONAL TEST CONFERENCE  
November 3-5, 2020

## **TTTC Awards Presentation**

**Yervant Zorian**

**TTTC Lifetime Contribution Medal**

**Hideo Fujiwara**



## TTTC President

Yervant Zorian  
Synopsis

## TTTC Lifetime Contribution Medal

- Outstanding Technical Contribution
- Fundamental Impact on Test Technology
- Presented at Flagship TTTC Event
- Feature Article in IEEE Design & Test
- Open Nominations - July 15



Yervant

# TTTC Lifetime Contribution Medal



E. Eichenberger



A. J. Aronoff



E.J. McQuinn



J. Mitsu



R. Tullias



P. H. Bordet



J. N. Aronoff



W. Mathewy



T.M. Williams



M. Bruner



V.D. Agnew



J.P. Hayes



W.P. Maly



V. K. Agnew



J. Patel



R. Overton



J. Abruzzo



B. Krasnowski



Kathleen Rostky



M. Ray Mercer



Yervant





Hideo Fujiwara



## Hideo Fujiwara

- M.E. – Electronic Eng, Osaka University, 1971
- Ph.D. – Electronic Eng., Osaka University, 1974
- Assistant Professor, Osaka University, 1974 – 1985
- Professor, Meiji University, 1985 – 1993
- Professor, Nara Inst of Science and Technology, 1993 – 2011
- Professor - Osaka Gakuin University, present
- Published over 450 paper, many best papers
- Authored 11 books – Logic Testing & DFT, textbook, 1985



## Honors & Contributions

- FAN algorithm – Fastest ATPG algorithm, adopted by industry, 1983
- ISCAS '85 benchmarks
- Fellow of IEEE 1989; Life Fellow of IEEE, 2012



Yervant





## Honors & Contributions

- FAN algorithm – Fastest ATPG algorithm, adopted by industry, 1983
- ISCAS '85 benchmarks
- Fellow of IEEE 1989; Life Fellow of IEEE, 2012
- Program Chair, 1<sup>st</sup> ATS, 1991
- General Chair, 3<sup>rd</sup> ATS, 1993
- Chair, ATS Steering Committee
- Chair, TTC Asia and Pacific Region
- Co-Founder, RTL and High-Level Test Wkshp.
- IEEE CS Meritorious Award, 1996
- IEEE CS Outstanding Contribution, 2001, 2009, 2016





## Hideo Fujiwara

- Innovator
- Leader
- Pioneer in test technology
- Lasting impacts to test community





**Yervant**



**Hideo Fujiwara**